

PTO-1449	Application No. 10/825,539		Applicant(s) James D. Ballew, et al.	
	Docket Number 064747.1014	Group Art Unit 2451	Filing Date April 15, 2004	

**INFORMATION DISCLOSURE CITATION
IN AN APPLICATION**

U.S. PATENT DOCUMENTS

		DOCUMENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE
	A	6,691,165 B1	02/10/2004	Bruck, et al.	709	227	04/12/2000
	B	2003/0005039 A1	01/02/2003	Craddock, et al.	709	203	06/29/2001
	C						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
	D	JP 7200496	08/04/1995	Japan	G06F	15/16	Abstract Only	
	E	JP 2007141305	06/07/2007	Japan	G11B	21/10	Abstract Only	
	F							

		DOCUMENT (Including Author, Title, Source, and Pertinent Pages)	DATE
	G	USPTO; Notice of Allowance and Fee(s) Due for Application No. 10/826,959 filed 04/15/2004 in the name of James D. Ballew; Examiner Elmira Mehrmanesh; Attorney Docket No. 064747.1015; 4 pages.	05/12/2009
	H	Korean International Patent Office; Notice of Last Preliminary Rejection for Application No. 10-2006-7023880; 5 pages.	05/28/2009
	I	Korean International Patent Office; Notice of Last Preliminary Rejection English Translation for Application No. 10-2006-07023880; 4 pages.	05/28/2009
	J	Canadian Intellectual Property Office; Office Action for Application No. 2,503,773; 3 pages.	06/04/2009
	K	USPTO; Advisory Action for Application No. 10/825,345 filed 04/15/2004 in the name of Shannon V. Davidson; Examiner Saket K. Daftuar; Attorney Docket No. 064747.1011; 3 pages.	06/25/2009
	L	USPTO; Office Action for Application No. 10/824,873 filed 04/15/2004 in the name of Shannon V. Davidson; Examiner William J. Goodchild; Attorney Docket No. 064747.1016; 11 pages.	06/25/2009
	M	Japanese Patent Office; Translation of an Office Action for Application No. 2005-117403; 1 page.	06/26/2009
	N	Japanese Patent Office; Translation of an Office Action for Application No. 2005-117404; 1 page.	06/26/2009
	O	Japanese Patent Office; Translation of an Office Action for Application No. 2005-117406; 1 page.	06/26/2009
	P		

EXAMINER

DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.

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